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**** CONTINUING DATA *******

**** FOREIGN APPLICATIONS *******

JAPAN 2002-214476 07/23/2002
 JAPAN 2003-020663 01/29/2003
 JAPAN 2003-270360 07/02/2003

verifred J.m.H.

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

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Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY	SHEETS	TOTAL	INDEPENDENT
35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance	JAPAN	DRAWING 15	CLAIMS 31	CLAIMS 8
Verified and Acknowledged	<i>John M. Hiltner</i> Examiner's Signature	Initials			

ADDRESS

23850
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TITLE

Probe card and testing method of semiconductor chip, capacitor and manufacturing method thereof

<input type="checkbox"/> All Fees
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